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## Explore intrinsically electrical characteristics of atomically thin SnS<sub>2</sub> flake

### Abstract

The interface problems in nanowire-based electronics play important roles in nanoelectronics multiply enormously the contribution of electrical contact properties. Here, the intrinsically electrical characteristics of atomically thin SnS<sub>2</sub> field effect transistor (FET) device were explored in detail. Four layers (c.a. 2.3 nm) of SnS<sub>2</sub> flakes were obtained via mechanical exfoliation from a semiconducting SnS<sub>2</sub> bulk crystal grown by chemical vapor transport and then deposited on a heavily doped Si substrate covered with a 285-nm-thick SiO<sub>2</sub> layer. The number of layers for SnS<sub>2</sub> flakes was quickly determined by images existing difference in the contrast of the color of optical microscope and atomic force microscope. To investigate the electrical properties of atomically thin SnS<sub>2</sub> flakes, SnS<sub>2</sub> FETs were fabricated using standard e-beam lithography and thermal evaporation. As the experimental results, the good performance, including a high on/off ratio up to 10<sup>5</sup> and a mobility ~3.2 cm<sup>2</sup>V<sup>-1</sup>s<sup>-1</sup>, of SnS<sub>2</sub> FET applied in this study can be achieved. Moreover, on the basis of analysis of temperature dependent resistance between two- and four-terminal FETs, we found that the resistance increases with temperature decreasing. The contact resistance can be extracted to c. 5 % of total resistance, implying the contact resistance can be eliminated without additional treatment during fabrication processes of SnS<sub>2</sub> FETs. Besides, we report the unprecedented measurements, low frequency noise, of SnS<sub>2</sub>-based FETs. The measured results provide detailed insights of the electrical properties of SnS<sub>2</sub> FETs for the first time, might be useful for optoelectronic nanodevice applications in industrial.